

**Notice of References Cited**

Application/Control No.

10/521,242

Applicant(s)/Patent Under  
Reexamination  
OGAWA, MIKI

Examiner

NATHAN H. EMPIE

Art Unit

1792

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2006/0057296	03-2006	Ogawa et al.	427/377
	C	US-			
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	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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